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## Wetting on smooth micropatterned defects

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We develop a 2D model which predicts the contact angle hysteresis (CAH) introduced by smooth micropatterned defects. The defects are modeled by a smooth function, and the CAH is explained using a tangent line solution. When the liquid micro-meniscus touches both sides of the defect simultaneously, depinning of the contact line occurs and the droplet “pops-up.” The defects are fabricated using the photoresist SU-8. The experimental results, using common liquids (water, isopropyl alcohol, and ethylene glycol), agree well with the predictions of the model. The profile of the defect has a large influence on the CAH. © 2011 American Institute of Physics.

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When a sessile droplet contracts (e.g., via evaporation) or swells (e.g., via condensation), the contact line (i.e., the liquid-vapor-solid interface) moves according to the contact angle hysteresis (CAH);<sup>1–7</sup> this effect is fundamental for many modern applications.<sup>8–11</sup> In contrast to tuning the CAH by controlling defect length,<sup>12</sup> here, we demonstrate that the CAH can be modified using the defect profile corresponding to a tangent line solution for the depinning of the micro-meniscus of a droplet.

We consider here the CAH introduced by a smooth defect<sup>5</sup> in an idealized flat surface. We assume that the defect can be modeled by a function  $h(x)$  which is smooth in the mathematical sense. First, let us consider the *microscopic* contact angle  $\bar{\theta}$  in the vicinity of the micro-meniscus. If the contact line moves (Fig. 1), we consider  $\bar{\theta}$  is constant relative to the surface tangent. We assume the profile of the micro-meniscus to be that of a straight line. Fig. 1(a) is an advancing contact line where the micro-meniscus does not touch the right hand side (rhs) of the defect as the contact line moves over the defect. Fig. 1(b) is an advancing contact line where the micro-meniscus does touch the rhs of the defect. Fig. 1(c) is a receding contact line where the micro-meniscus does not touch the left hand side (lhs) of the defect. Fig. 1(d) is a receding contact line where the micro-meniscus *does touch* the lhs of the defect. In all cases, the centre of the droplet is considered to be to the left of the defect.  $\bar{\theta}_{r,a}^*$  in Fig. 1 refers to the effective microscopic contact angle with respect to the horizontal plane when the contact line depins from the defect.

Let us now consider the case of the receding contact line in more detail (the arguments apply equally to the advancing contact line via symmetry). When the contact line encounters the defect, it moves down the rhs ( $x > 0$ ) of the defect,  $\bar{\theta}_r$  remains constant; the result of this is that the macroscopic contact angle with respect to the horizontal plane reduces. It is important now to make a physical distinction between the liquid micro-meniscus touching the lhs ( $x < 0$ ) of the defect or not.

If the micro-meniscus does not touch the opposite side of the defect [Fig. 1(c)] then the *effective* receding contact angle introduced by the defect is given by  $\bar{\theta}_r^* = \bar{\theta}_r - \tan^{-1}[h'(x_p)]$ , where  $x_p$  is the point of inflection<sup>1</sup> on the rhs of  $h(x)$ .

If the liquid meniscus touches the lhs of the defect<sup>3</sup> (at  $x = x_i$ ), then  $\bar{\theta}_r^*$ , which is given by  $\tan^{-1}[h'(x_i)]$ , is equal to  $\bar{\theta}_r - \tan^{-1}[h'(x_i)]$ ; in this case, the relationship between  $\bar{\theta}_r$  and  $\bar{\theta}_r^*$  is non-linear. This is the tangent line at  $x_i$  which also intersects  $h(x)$  at  $x = x_i$ ; this case is illustrated in Fig. 1(d). By symmetry,  $\bar{\theta}_a^*$  is given by  $\bar{\theta}_a - \tan^{-1}[h'(x_i)]$  by using the same arguments above but with the contact line moving from left to right [Fig. 1(b)]. Continuing the receding angle case, once the micro-meniscus touches the lhs of the defect at  $x_i$ , it will break as the contact line will not be stable at  $x_i$ ; as a consequence, the contact line will depin. Thus, the required tangent line cuts  $h(x)$  at two points: the tangent point ( $x_i$ ) on the lhs of the defect and the intersection point ( $x_i$ ) on the rhs of the defect. Hence, we can write  $\bar{\theta}_{r,a}^* = \tan^{-1}[h'(x_i)]$  and  $\tan^{-1}[h'(x_i)] = \bar{\theta}_{r,a} - \tan^{-1}[h'(x_i)]$  together with the tangent line  $h(x_i) - h(x_i) = h'(x_i)(x_i - x_i)$ . As  $h(x)$  is a smooth function, it follows that we should be able to resolve the problem in terms of simple parameters (the defect depth  $h_0$ , the defect width  $w$  and  $\bar{\theta}_{r,a}$ ).

The micropatterned defects can be modeled using a cosine function over a single period:  $h(x) = -1/2 h_0 (\cos(2\pi x/w) + 1)$ , where  $h_0$  and  $w$  are described above. Two tangent line solutions exist for the given values of  $\bar{\theta}_r$  and  $\bar{\theta}_a$ ; the required solution is the tangent line which intersects  $h(x)$  above its

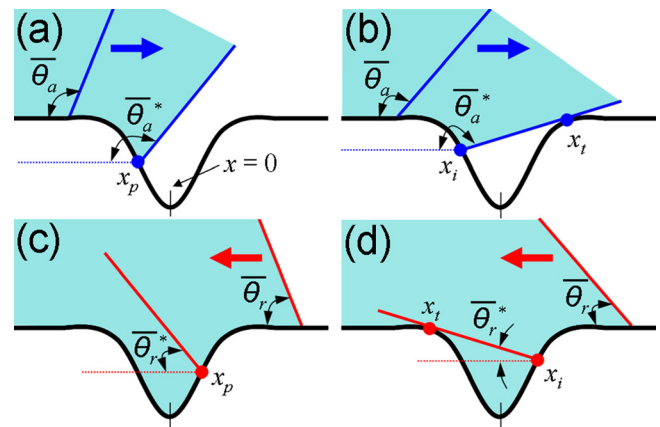


FIG. 1. (Color online) A contact line moving across a surface containing a smooth defect for (a) and (b) an advancing contact line and (c) and (d) a receding contact line.

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TABLE I. Summary of findings. (a) SU-8 and (b) FC.

Liquid	Experiment.				Calculations	
	$\theta_r$	$\theta_a$	$\theta_r^*$	$\theta_a^*$	$\bar{\theta}_r^*$	$\bar{\theta}_a^*$
H <sub>2</sub> O <sup>(a)</sup>	62.2° ± 2.8	91.8° ± 0.5	5.6° ± 1.3	147° ± 2	6.8°	154.7°
H <sub>2</sub> O <sup>(b)</sup>	97.9° ± 2.3	114.1° ± 2.1	34.6° ± 3.4	159.3° ± 7.7	35°	171.6°
C <sub>2</sub> H <sub>6</sub> O <sub>2</sub> <sup>(a)</sup>	29.9° ± 1.5	55° ± 0.6	4° ± 0.7	119.2° ± 1.7	0.8°	118°
C <sub>2</sub> H <sub>6</sub> O <sub>2</sub> <sup>(b)</sup>	70.2° ± 1.3	123.9° ± 1.5	14.2° ± 1	152.6° ± 4.7	10.7°	175.3°
IPA/H <sub>2</sub> O (2.5/97.5) <sup>(b)</sup>	88.5° ± 4.3	102.7° ± 1.4	24.3° ± 3.3	151.3° ± 4.5	25.5°	164.5°
IPA/H <sub>2</sub> O (5/95) <sup>(b)</sup>	84.3° ± 1.8	98.3° ± 1	21.6° ± 3.2	147.7° ± 1.8	21.3°	161°
IPA/H <sub>2</sub> O (10/90) <sup>(a)</sup>	44.5° ± 1.2	72.9° ± 1.1	4.9° ± 0.1	137.6° ± 4.6	2.3°	135.9°

Observation of menisci at the millimeter-scale is relatively simple,<sup>14</sup> whereas micro-menisci contact angles measurements are challenging.<sup>15–17</sup> Here, the CAH was measured using droplet expansion (syringe pump) and evaporation.<sup>18</sup> We verified that evaporation and syringe methods give the same results for contact angle measurements. In order to measure the macroscopic receding and advancing contact angles ( $\theta_r$ ,  $\theta_a$ ,  $\theta_r^*$ ,  $\theta_a^*$ ) using the syringe method, a small droplet of liquid ( $vol \sim 0.3$  nL) was positioned onto the smallest concentric circle ( $\varphi = 100$   $\mu$ m) at the centre of the micropatterned surface and swelled using a syringe pump ( $1\text{--}5$   $\mu$ L min<sup>−1</sup>) in order to measure  $\theta_a$  and  $\theta_a^*$ . Once the droplet diameter was larger than the largest concentric circle in the micropattern ( $\varphi = 2$  mm), the droplet volume was reduced using the syringe ( $1\text{--}5$   $\mu$ L min<sup>−1</sup>) in order to measure  $\theta_r$  and  $\theta_r^*$ . For the evaporation tests, a droplet ( $vol \sim 2$   $\mu$ L) was placed on the micropatterned surface and allowed to slowly evaporate (unforced), whilst the values of  $\theta_r$  and  $\theta_r^*$  were recorded as a function of time. This evaporation method was not possible for ethylene glycol due to a low vapor pressure at room temperature;<sup>19</sup> however, evaporation tests were possible using IPA/H<sub>2</sub>O solutions as the vapor pressure of IPA and of water are very similar at room temperature.<sup>19</sup>

Fig. 3(a) shows a typical droplet evaporation sequence recorded for a micropattern. The contact line becomes pinned onto a circular defect at  $t = 431$  s. The apparent contact angle reduces until the effective contact angle  $\theta_r^*$  is attained, whereby the droplet suddenly depins and “pops-up” at  $t = 661$  s; the droplet subsequently pins to the next smallest circle defect and the process repeats one more time. Fig. 3(b) shows the data gathered over a period of 375 s for an evaporating droplet (IPA/H<sub>2</sub>O) on a FC coated SU-8 surface. Three distinct phases are apparent: Phases (1) and (2) correspond to droplet evaporation at constant contact angle with diminishing droplet base radius<sup>18</sup> followed by constant base radius and diminishing contact angle.<sup>18</sup> When the droplet is not pinned to a defect and phase (3), an evaporating droplet depinning from circle to circle where the contact angle follows a saw-tooth variation<sup>3,4,6</sup> with  $\theta_r^*$  constant. This sawtooth profile increases in amplitude according to the equation given in the inset. As the droplet depins from circle to circle, since the volume is constant at each depinning,  $\theta_2$  must be larger at each depinning cycle (distance between circles  $D$  constant); the evaporation between the depinnings is described as in Ref. 18.

Fig. 4 shows a plot of the experimentally obtained values of  $\theta_r^*$  and  $\theta_a^*$  as a function of  $\theta_r$  and  $\theta_a$  for various liquids on

surfaces containing smooth micropatterned defects. Our measurements indicate that the microscopic model can accurately predict the values of  $\theta_r^*$  introduced by the defect, thus giving a strong evidence for the tangent line solution model for the macroscopic CAH introduced by a smooth defect. The inset to Fig. 4(a) illustrates good agreement between the experimental defect and the model. Despite the defect not being a perfect cosine shape, the parameters  $h_0$  and  $w$  enable a good fit between the real defect shape and the model in the region where the liquids depin. Theoretical<sup>3</sup> and experimental<sup>4</sup> studies on CAH induced by sinusoidal defects have been performed, although neither resolved the tangent line depinning problem.

Let us now consider the experimental results for  $\theta_a^*$  shown in Fig. 4(b). Due to the finite needle diameter, the values of  $\theta_a^*$  were measured at droplet base radii between 0.5–1 mm. Two liquid/surface combinations fit very well with the predictions of the model and five deviate from the model. In order to explain this, horizontal bars have been added to Fig. 4(b), which indicate the value of contact angle calculated using a base radius  $r$  of 0.75 mm and equating the droplet diameter  $D$  to the capillary length  $(\gamma/\rho g)^{1/2}$  of the liquid. These bars represent the maximum values of  $\theta_a^*$  before gravity becomes non-negligible<sup>3,4</sup> and vibrations are known to cause depinning.<sup>20</sup> Table I gives a summary of all results.

<sup>1</sup>R. Shuttleworth and G. L. J. Bailey, *Discuss. Faraday Soc.* **3**, 16 (1948).

<sup>2</sup>R. E. Johnson and R. H. Dettre, *J. Phys. Chem.* **68**, 1744 (1964).

<sup>3</sup>C. Huh and S. G. Mason, *J. Colloid Interface Sci.* **60**, 11 (1977).

<sup>4</sup>J. P. Oliver, C. Huh, and S. G. Mason, *Colloids Surf.* **1**, 79 (1980).

<sup>5</sup>J. F. Joanny and P. G. De Gennes, *J. Chem. Phys.* **81**, 552 (1984).

<sup>6</sup>H. Kusumaatmaja and J. M. Yeomans, *Langmuir* **23**, 6019 (2007).

<sup>7</sup>M. Reyssat and D. Quéré, *J. Phys. Chem. B* **113**, 3906 (2009).

<sup>8</sup>R. Blossey, *Nature Mater.* **2**, 301 (2003).

<sup>9</sup>X. J. Feng and L. Jiang, *Adv. Mater.* **18**, 3063 (2006).

<sup>10</sup>G. M. Whitesides and B. Grzybowski, *Science* **295**, 2418 (2002).

<sup>11</sup>J. B. Hannon, S. Kodambaka, F. M. Ross, and R. M. Tromp, *Nature* **440**, 69 (2006).

<sup>12</sup>D. Debuissou, V. Senez, and S. Arscott, *Appl. Phys. Lett.* **98**, 184101 (2011).

<sup>13</sup>D. Debuissou, V. Senez, and S. Arscott, *J. Micromech. Microeng.* **21**, 065011 (2011).

<sup>14</sup>W. Choi, A. Tuteja, J. M. Mabry, R. E. Cohen, and G. H. McKinley, *J. Colloid Interface Sci.* **339**, 208 (2009).

<sup>15</sup>H. Rathgen, K. Sugiyama, C.-D. Ohl, D. Lohse, and F. Mugele, *Phys. Rev. Lett.* **99**, 214501 (2007).

<sup>16</sup>C. Jourmet, S. Moulinet, C. Ybert, S. T. Purcell, and L. Bocquet, *Europhys. Lett.* **71**, 104 (2005).

<sup>17</sup>J.-G. Fan and Y.-P. Zhao, *Nanotechnology* **19**, 155707 (2008).

<sup>18</sup>R. G. Picknett and R. Bexon, *J. Colloid Interface Sci.* **61**, 336 (1977).

<sup>19</sup>*CRC Handbook of Chemistry and Physics*, 69th ed., edited by R. C. Weast (CRC, Florida, USA).

<sup>20</sup>P. Brunet, J. Eggers, and R. D. Deegan, *Eur. Phys. J.* **166**, 11 (2009).